

Note: This is a draft of an abstract submitted for publication. Contents of this abstract should not be quoted or referred to without permission of the author(s).

To be submitted to the Microscopy and Microanalysis 2002 meeting, Quebec City, Canada, August 4-8, 2002.

STEM Investigations of Defects and Interfaces In Complex Oxides

S. J. Pennycook¹, M. Varela¹, J. Santamaria², D. Kumar³ and G. Duscher^{1,4},

¹ Solid State Division, Oak Ridge National Laboratory, Oak Ridge, Tennessee.

² Departamento de Fisica Aplicada III, Universidad Complutense de Madrid, 28040 Madrid. Spain

³ Ctr for Advanced Materials & Smart Structures, North Carolina A & T State University, Greensboro, N.C.

⁴ Dept. of Materials Science and Engineering, North Carolina State University, Raleigh, N.C.

“The submitted manuscript has been authored by a contractor of the U.S. Government under contract No. DE-AC05-00OR22725. Accordingly, the U.S. Government retains a nonexclusive, royalty-free license to publish or reproduce the published form of this contribution, or allow others to do so, for U.S. Government purposes.”

prepared by
SOLID STATE DIVISION
METALS AND CERAMICS DIVISION
OAK RIDGE NATIONAL LABORATORY
Managed by
UT-BATTELLE, LLC.
under
Contract No. DE-AC-05-00OR22725
with the
U.S. DEPARTMENT OF ENERGY
Oak Ridge, Tennessee

March 2002